

Sean Oshea

List of Publications by Year in descending order

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papers

545
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840776

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docs citations

18
times ranked

560
citing authors

#	ARTICLE	IF	CITATIONS
1	Dielectric Breakdown in Single-Crystal Hexagonal Boron Nitride. ACS Applied Electronic Materials, 2021, 3, 3547-3554.	4.3	28
2	Localized Probing of Dielectric Breakdown in Multilayer Hexagonal Boron Nitride. ACS Applied Materials & Interfaces, 2020, 12, 55000-55010.	8.0	11
3	Correlation of Dielectric Breakdown and Nanoscale Adhesion in Silicon Dioxide Thin Films. , 2020, , .		2
4	The interplay between drift and electrical measurement in conduction atomic force microscopy. Review of Scientific Instruments, 2019, 90, 073701.	1.3	8
5	Boron Vacancies Causing Breakdown in 2D Layered Hexagonal Boron Nitride Dielectrics. IEEE Electron Device Letters, 2019, 40, 1321-1324.	3.9	16
6	Effect of Electric Field and Trace Water on Confined Undecanol and Tetradecane. Journal of Physical Chemistry C, 2018, 122, 3326-3333.	3.1	0
7	Conductive Atomic Force Microscope Study of Bipolar and Threshold Resistive Switching in 2D Hexagonal Boron Nitride Films. Scientific Reports, 2018, 8, 2854.	3.3	55
8	Reply to the "Comment on: A Note on the Two-Spring Tomlinson Model". Tribology Letters, 2012, 45, 227-228.	2.6	0
9	Characterization of tips for conducting atomic force microscopy in ultrahigh vacuum. Review of Scientific Instruments, 1998, 69, 1757-1764.	1.3	55
10	Potentiometry and repair of electrically stressed nanowires using atomic force microscopy. Applied Physics Letters, 1998, 72, 915-917.	3.3	51
11	Lateral stiffness of the tip and tip-sample contact in frictional force microscopy. Applied Physics Letters, 1997, 70, 970-972.	3.3	142
12	Micromechanical Stress Sensors for Electrochemical Studies. Materials Research Society Symposia Proceedings, 1996, 451, 37.	0.1	0
13	A near-field optical microscope with normal force distance regulation. Review of Scientific Instruments, 1996, 67, 3891-3897.	1.3	3
14	Conducting AFM: Applications to Semiconductor Surfaces. Materials Research Society Symposia Proceedings, 1995, 386, 371.	0.1	1
15	Direct writing of nanostructures from silane on silicon (111). Applied Physics Letters, 1995, 67, 786-788.	3.3	14
16	Characterization of tips for conducting atomic force microscopy. Review of Scientific Instruments, 1995, 66, 2508-2512.	1.3	90
17	Magnetic force microscope study of local pinning effects. Journal of Applied Physics, 1994, 76, 418-423.	2.5	15
18	Force microscopy imaging in liquids using ac techniques. Applied Physics Letters, 1994, 65, 409-411.	3.3	54